

Japan-U.S. Symposium on International Standardization Toward a Low Carbon Society

February 15, 2010

Auditorium (2F) Conference Room

AIST Tsukuba Central 1, Tsukuba, Japan



Sponsor:

National Institute of Advanced Industrial Science and Technology (AIST)

This symposium is supported by the Ministry of Economy, Trade and Industry (METI) in the framework of "Japan-US collaboration project toward a novel low carbon society".

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9:45-10:30 Opening

Chair: T. Takatsuji (AIST, Japan)

- **Akira Ono**, Senior Vice-President, AIST
- **Hironori Nakanishi**, Director, Technical Regulations, Standards and Conformity Assessment Policy Division, Industrial Science and Technology Policy and Environment Bureau, METI
- **Magdalena Navarro**, Senior International Program Manager, OIAA, Director's Office, NIST, "*NIST-AIST Research Activities under the MOU*"

10:30-12:15 Session 1 [Environment and Energy Standardization]

Chair: T. Takatsuji (AIST, Japan)

S1-1 Information Security

- **Annabelle Lee** (via video), Computer Security Division, Information Technology Laboratory, NIST, "*Smart Grid and Cyber Security*"
- **Hirofumi Sakane**, Research Center for Information Security, AIST, "*FIPS 140-3 Non-Invasive Attack Testing*"

S1-2 Solid State Lighting

- **Tatsuya Zama**, Photometry and Radiometry Division, National Metrology Institute of Japan, AIST, "*Development of Photometric Measurement Techniques for Solid State Lighting (SSL)*"
- **Yoshi Ohno**, Optical Technology Division, Physics Laboratory, NIST, "*NIST's Role in Standardization of Solid State Lighting*"

S1-3 3D Imaging

- **Chris Chinnock**, Board Member, 3D@Home Consortium, "*3D Trends, Opportunities and Challenges*"
- **Hiroyasu Ujike**, Institute for Human Science and Biomedical Engineering, AIST, "*3D Image Safety: R&D for the Guidelines*"

12:15-13:20 Lunch

13:20-14:45 Session 2 [Nanotechnology Standardization I]

Chair: S. Kazaoui (AIST, Japan)

S2-1 Thickness

- **Yasushi Azuma**, Materials Characterization Division, National Metrology Institute of Japan, AIST, “*Development of Thin Film Standards for Thickness Metrology by X-ray Reflectometry*”
- **Donald Windover**, Ceramics Division, Materials Science and Engineering Laboratory, NIST, “*NIST SI-traceable X-Ray Reflectometry (XRR) Measurement Capabilities for Thin Films: Instrumentation and Data Analysis*”

S2-2 Thermal and Mechanical Properties

- **Naoyuki Taketoshi**, Material Properties and Metrological Statistics Division, National Metrology Institute of Japan, AIST, “*Thermophysical Property Standard for Thin Films in Japan*”
- **Joshua Martin**, Ceramics Division, Materials Science and Engineering Laboratory, NIST, “*Thermoelectric and Thermophysical Metrology for Energy Conversion Applications*”
- **Koichiro Hattori**, Acoustics and Vibration Metrology Division, National Metrology Institute of Japan, AIST, “*Nanoindentation and Hardness Standards*”

14:45-15:05 Coffee Break

15:05-16:50 Session 3 [Nanotechnology Standardization II]

Chair: K. Hattori (AIST, Japan)

S3-1 Form and Dimension

- **Hiroshi Itoh**, Research Institute of Instrumentation Frontier, AIST, “*AFM Probe Characterization*”
- **Ndubuisi Orji**, Precision Engineering Division, Manufacturing Engineering Laboratory, NIST, “*Traceable AFM Dimensional Metrology at NIST: Applications and Areas of Collaboration*”
- **Satoshi Gonda**, Length and Dimensions Division, National Metrology Institute of Japan, AIST, “*Development of Metrological AFMs and Nanoscale Standards*”

S3-2 Nano-carbon Materials, Carbon Nanotubes and Fullerenes

- **Said Kazaoui**, Nanotube Research Center, AIST, “*Selective Extraction and Properties of Semiconducting Carbon Nanotubes*”
- **Vivek Prabhu**, Polymers Division, Materials Science and Engineering Laboratory, NIST, “*Optical Methods to Probe Stable Carbon Nanotube Dispersions and pH-induced Aggregation of Nanoparticles*”

- **Gerald Fraser**, Optical Technology Division, Physics Laboratory, NIST,
*“Physicochemical Characterization of Engineered Nanoparticles: The measurands
that influence Nano EHS”*

16:50-17:00 Closing

- **Mitsuru Tanaka**, Research Coordinator, AIST